Document No.	
ECN No.	
Date of Issue	July 30, 1990
Status	Preliminary Specification
ACL Products	

74AC11377

Octal D-type flip-flop with enable

FEATURES

- Eight edge-triggered D-type flip-flops
- Buffered common clock
- Buffered clock enable
- Output capability: ±24 mA
- CMOS (AC) and TTL (ACT) voltage level inputs
- 50Ω incident wave switching
- Center-pin V_{CC} and ground configuration to minimize high-speed switching noise
- I_{CC} category: MSI

DESCRIPTION

The 74AC/ACT11377 high-performance CMOS devices combine very high speed and high output drive comparable to the most advanced TTL families.

The 74AC/ACT11377 provides eight positive edge-triggered D-type flip-flops with individual Data inputs and Q outputs. The common buffered Clock (CP) input loads all flip-flops simultaneously when the Enable ($\overline{E}$) is Low.

The $\overline{E}$ input must be stable one setup time prior to the Low-to-High clock transition for predictable operation.

QUICK REFERENCE DATA

SYMBOL	PARAMETER	CONDITIONS T_{amb} = 25°C; GND = 0V; V_{CC} = 5.0V	TYPICAL AC	TYPICAL ACT	UNIT
t_{PLH}/ t_{PHL}	Propagation delay CP to Q_n	C_L = 50pF	7.2		ns
C_{PD}	Power dissipation capacitance per flip-flop[1]	f = 1MHz; C_L = 50pF	72		pF
C_{IN}	Input capacitance	V_I = 0V or V_{CC}	4.0	4.0	pF
I_{LATCH}	Latch-up current	Per Jedec JC40.2 Standard 17	500	500	mA
f_{MAX}	Maximum clock frequency	C_L = 50pF	100		MHz

Note:

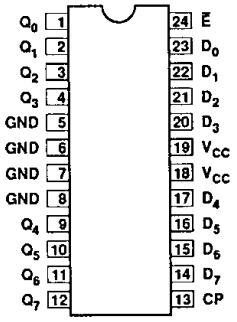
1. C_{PD} is used to determine the dynamic power dissipation (P_D in µW):
   $P_D = C_{PD} \times V_{CC}^2 \times f_i + \Sigma (C_L \times V_{CC}^2 \times f_O)$ where:
   f_i = input frequency in MHz, C_L = output load capacitance in pF,
   f_O = output frequency in MHz, V_{CC} = supply voltage in V,
   $\Sigma (C_L \times V_{CC}^2 \times f_O)$ = sum of outputs

ORDERING INFORMATION

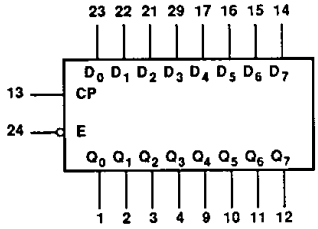
PACKAGES	TEMPERATURE RANGE	ORDER CODE
24-pin plastic DIP (300mil-wide)	-40°C to +85°C	74AC11377N 74ACT11377N
24-pin plastic SOL (300mil-wide)	-40°C to +85°C	74AC11377D 74ACT11377D

PIN CONFIGURATION

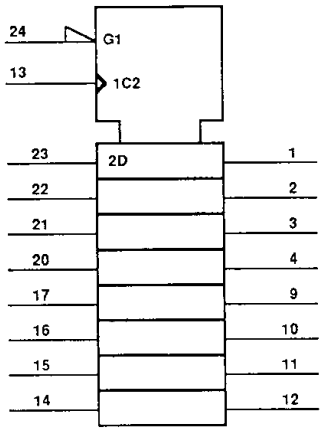
N and D Packages



LOGIC SYMBOL



LOGIC SYMBOL (IEEE/IEC)



Octal D-type flip-flop with enable

74AC/ACT11377

PIN DESCRIPTION

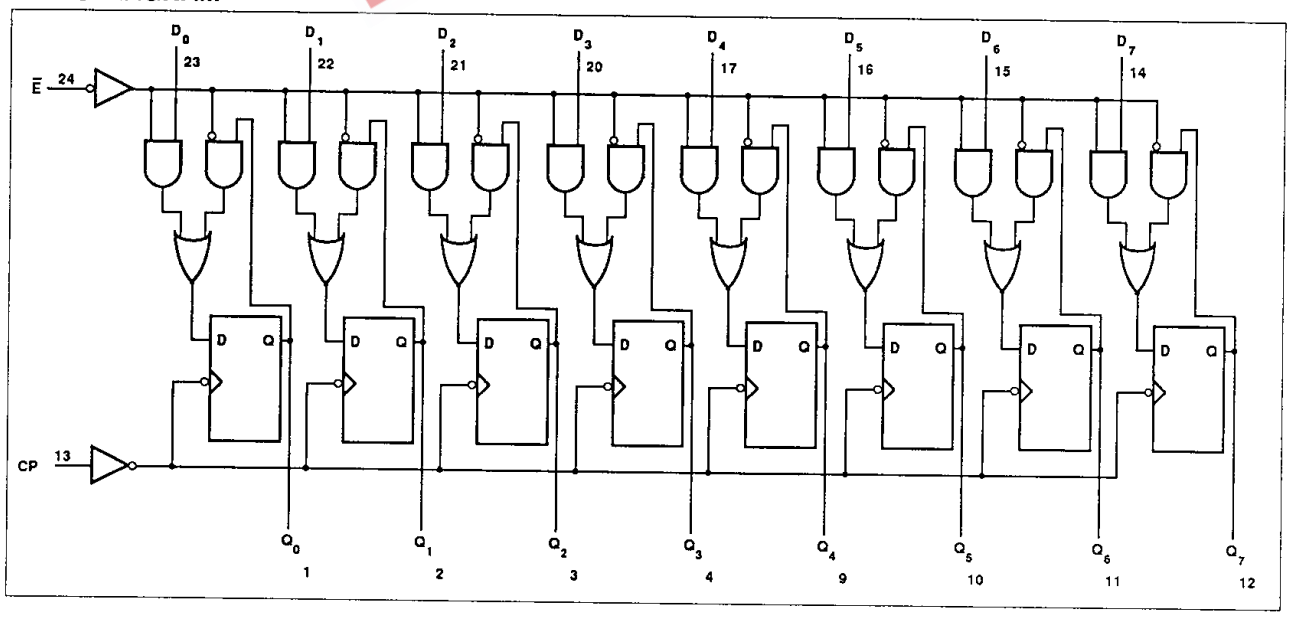
PIN NUMBER	SYMBOL	NAME AND FUNCTION
24	$\overline{E}$	Enable input (active-Low)
13	CP	Clock pulse input
23, 22, 21, 20, 17, 16, 15, 14	D_0 - D_7	Data inputs
1, 2, 3, 4, 9, 10, 11, 12	Q_0 - Q_7	Data outputs
5, 6, 7, 8	GND	Ground (0V)
18, 19	V_{CC}	Positive supply voltage

MODE SELECT—FUNCTION TABLE

OPERATING MODE	INPUTS			OUTPUTS
	CP	$\overline{E}$	D_n	Q_n
Load "1"	↑	l	h	H
Load "0"	↑	l	l	L
Hold (do nothing)	↑	h	X	no change
	X	H	X	no change

H = High voltage level steady state
h = High voltage level one setup time prior to the Low-to-High clock transition
L = Low voltage level steady state
l = Low voltage level one setup time prior to the Low-to-High clock transition
X = Don't care
↑ =Low-to-High clock transition

LOGIC DIAGRAM



Octal D-type flip-flop with enable 74AC/ACT11377

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	74AC11377			74ACT11377			UNIT
		Min	Nom	Max	Min	Nom	Max	
V_{CC}	DC supply voltage	3.0[1]	5.0	5.5	4.5	5.0	5.5	V
V_I	Input voltage	0		V_{CC}	0		V_{CC}	V
V_O	Output voltage	0		V_{CC}	0		V_{CC}	V
$\Delta t/\Delta v$	Input transition rise or fall rate	0		10	0		10	ns/V
T_{amb}	Operating free-air temperature range	-40		+85	-40		+85	°C

NOTE:
1. No electrical or switching characteristics are specified at V_{CC} < 3V. Operation between 2V and 3V is not recommended, but within that range, a device output will maintain a previously established logic state.

ABSOLUTE MAXIMUM RATINGS[1]

SYMBOL	PARAMETER	TEST CONDITIONS	RATING	UNIT
V_{CC}	DC supply voltage		-0.5 TO +7.0	V
I_{IK} or V_I	DC input diode current[2]	$V_I < 0$	-20	mA
		$V_I > V_{CC}$	20	
	DC input voltage		-0.5 to V_{CC} +0.5	V
I_{OK} or V_O	DC output diode current[2]	$V_O < 0$	-50	mA
		$V_O > V_{CC}$	50	
	DCoutput voltage		-0.5 to V_{CC} +0.5	V
I_O	DC output source or sink current per output pin	V_O = 0 to V_{CC}	±50	mA
I_{CC} or I_{GND}	DC V_{CC} current		±200	mA
	DC ground current		±200	
T_{STG}	Storage temperature		-65 to 150	°C
P_{TOT}	Power dissipation per package	Above 70°C; derate linearly by 8mW/K	500	mW
	Power dissipation per package Plastic surface mount (SO)	Above 70°C; derate linearly by 8mW/K	400	mW

NOTES:
1. Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
2. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

Octal D-type flip-flop with enable

74AC/ACT11377

DC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER	TEST CONDITIONS		V_{CC}	74AC11377				74ACT11377				UNIT
					T_{amb} = +25°C		T_{amb} = -40°C to +85°C		T_{amb} = +25°C		T_{amb} = -40°C to +85°C		
				V	Min	Max	Min	Max	Min	Max	Min	Max	
V_{IH}	High-level input voltage			3.0	2.10		2.10						V
				4.5	3.15		3.15		2.0		2.0		
				5.5	3.85		3.85		2.0		2.0		
V_{IL}	Low-level input voltage			3.0		0.90		0.90					V
				4.5		1.35		1.35		0.8		0.8	
				5.5		1.65		1.65		0.8		0.8	
V_{OH}	High-level output voltage	V_I = V_{IL} or V_{IH}	I_{OH} = -50μA	3.0	2.9		2.9						V
				4.5	4.4		4.4		4.4		4.4		
				5.5	5.4		5.4		5.4		5.4		
			I_{OH} = -4mA	3.0	2.58		2.48						
			I_{OH} = -24mA	4.5	3.94		3.8		3.94		3.8		
				5.5	4.94		4.8		4.94		4.8		
			I_{OH} = -75mA[1]	5.5			3.85				3.85		
V_{OL}	Low-level output voltage	V_I = V_{IL} or V_{IH}	I_{OL} = 50μA	3.0		0.1		0.1					V
				4.5		0.1		0.1		0.1		0.1	
				5.5		0.1		0.1		0.1		0.1	
			I_{OL} = 12mA	3.0		0.36		0.44					
			I_{OL} = 24mA	4.5		0.36		0.44		0.36		0.44	
				5.5		0.36		0.44		0.36		0.44	
			I_{OL} = 75mA[1]	5.5				1.65				1.65	
I_I	Input leakage current	V_I = V_{CC} or GND		5.5		±0.1		±1.0		±0.1		±1.0	μA
I_{CC}	Quiescent supply current	V_I = V_{CC} or GND, I_O = 0mA		5.5		8.0		80		8.0		80	μA
ΔI_{CC}	Supply current, TTL inputs High[2]	One input at 3.4V, other inputs at V_{CC} or GND		5.5						0.9		1.0	mA

NOTES:

1. Not more than one output should be tested at a time, and the duration of the test should not exceed 10ms.
2. This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0V or V_{CC}.

Octal D-type flip-flop with enable 74AC/ACT11377

AC ELECTRICAL CHARACTERISTICS AT 3.3V ±0.3V

SYMBOL	PARAMETER	WAVEFORM	74AC11377					UNIT
			T_{amb} = +25°C			T_{amb} = -40°C to +85°C		
			Min	Typ	Max	Min	Max	
f_{MAX}	Maximum clock frequency	1	60			60		ns
t_{PLH} t_{PHL}	Propagation delay CP to Q_n	1	4.0 4.9	9.8 11.4	15.7 18.0	4.0 4.9	17.9 19.9	ns
t_S	Setup time, High or Low D_n to CP	2	6.0			6.0		ns
t_H	Hold time, High or Low D_n to CP	2	0.0			0.0		ns
t_S	Setup time, High or Low $\overline{E}$ to CP	2	9.0			9.0		ns
t_H	Hold time, High or Low $\overline{E}$ to CP	2	0.0			0.0		ns
t_W	Clock pulse width High or Low	1	5.0			5.0		ns

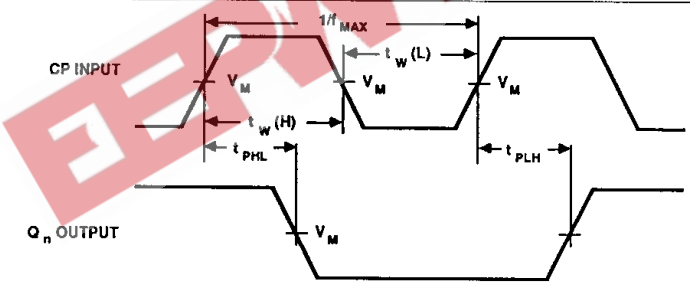
AC ELECTRICAL CHARACTERISTICS AT 5.0V ±0.5V

SYMBOL	PARAMETER	WAVEFORM	74AC11377					UNIT
			T_{amb} = +25°C			T_{amb} = -40°C to +85°C		
			Min	Typ	Max	Min	Max	
f_{MAX}	Maximum clock frequency	1	100			100		ns
t_{PLH} t_{PHL}	Propagation delay CP to Q_n	1	3.3 4.1	6.6 7.8	9.9 11.5	3.3 4.1	11.3 12.9	ns
t_S	Setup time, High or Low D_n to CP	2	4.0			4.0		ns
t_H	Hold time, High or Low D_n to CP	2	0.0			0.0		ns
t_S	Setup time, High or Low $\overline{E}$ to CP	2	6.0			6.0		ns
t_H	Hold time, High or Low $\overline{E}$ to CP	2	0.0			0.0		ns
t_W	Clock pulse width High or Low	1	5.0			5.0		ns

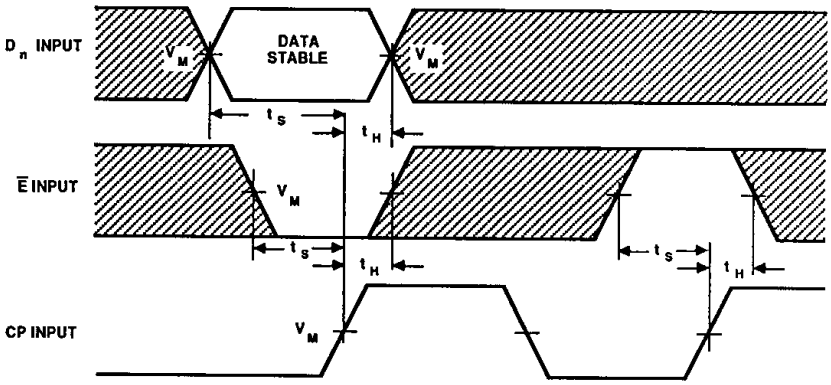
AC ELECTRICAL CHARACTERISTICS AT 5.0V ±0.5V

SYMBOL	PARAMETER	WAVEFORM	74ACT11377					UNIT
			T_{amb} = +25°C			T_{amb} = -40°C to +85°C		
			Min	Typ	Max	Min	Max	
f_{MAX}	Maximum clock frequency	1	100	125		100		ns
t_{PLH} t_{PHL}	Propagation delay CP to Q_n	1	4.5 4.8	9.1 9.6	12.2 12.7	4.5 4.8	13.8 14.2	ns
t_S	Setup time, High or Low D_n to CP	2	4.0			4.0		ns
t_H	Hold time, High or Low D_n to CP	2	1.0			1.0		ns
t_S	Setup time, High or Low $\overline{E}$ to CP	2	5.0			5.0		ns
t_H	Hold time, High or Low $\overline{E}$ to CP	2	0.0			0.0		ns
t_W	Clock pulse width High or Low	1	5.0			5.0		ns

WAVEFORMS



Waveform 1. Waveforms Showing the Propagation Delay, Input to Output, Clock Pulse Width, and Maximum Clock Frequency



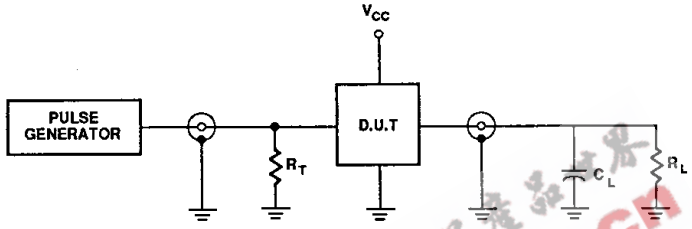
Waveform 3. Waveforms Showing the Data Set-up and Hold Times for the Input (D_n) and Parallel Enable Input ($\overline{E}$)

Octal D-type flip-flop with enable 74AC/ACT11377

WAVEFORM CONDITIONS

	INPUTS	OUTPUTS
AC	V_{IN} = GND to V_{CC}, V_M = 50% V_{CC}	V_{OUT} = V_{OL} to V_{OH}
ACT	V_{IN} = GND to 3.0V, V_M = 1.5V	V_M = 50% V_{CC}

TEST CIRCUIT



Test Circuit

DEFINITIONS

C_L = Load capacitance, 50pF; includes jig and probe capacitance

R_L = Load resistor, 500Ω

R_T = Termination resistance should be equal to Z_{OUT} of pulse generators

Input pulses: PRR ≤ 10MHz

$t_r = t_f$ = 3ns